

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Wayne A. Britson and Daniel A. Flores-Ibarra
Serial No. : 10/733,693
Filed : December 11, 2003
For : METHODS AND APPARATUS FOR TESTING AN IC
Examiner : Samir Wadie Rizk
Group Art Unit : 2112

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE AFTER FINAL

Sir:

In response to the final Office Action mailed August 8, 2007, Applicants respectfully request entry of the following remarks into the official record of the above-identified application:

A Listing of Claims begins on page 2 of this paper.

Remarks/Arguments begin on page 9 of this paper.